Call for Participation. We do not want to miss a single summer! BELAS is organized twice a year during the summers in the Northern and Southern Hemispheres. The first event will focus on reliability. Distinguished experts from Latin America will share their knowledge with European PhD and MSc students and postdocs. Participation fee is covered by sponsors. Participants are invited to present their research at the PhD Forum.

Technical Program

Dhiraj Pradhan, Bristol, UK, (Keynote) “Fundamentals of Computer Redundancy Techniques”
Fabian Vargas, PUCRS, Brazil, "Combined Effects of Radiation, EMI and Aging in Modern ICs: Comprehension and Current Solutions"
Victor Champac, INAOE, Mexico, “NBTI Aging in Scaled CMOS Technologies”
Letícia Bolzani Pöhls, PUCRS, Brazil, “Challenges in Nano-Scale Integrated Circuits Design: From CMOS to Graphene Devices”
José Lipovetzky, UBA, Argentina, "Ionizing Radiation Effects on Integrated Circuits and Test Procedures"
Said Hamdioui, TU Delft, Netherlands, (European expert), "IC Reliability: Failures, Modeling and Characteristics Quantification"

Thursday hands-on labs:
- JTAG/IJTAG with Göpel Equipment, Artur Jutman, Testonica, Estonia
- Combined Effects of Radiation, EMI and Aging, Latin American speakers

PhD Forum

The forum is a great opportunity for the attending PhD students to discuss their research work with the speakers and other participants. It is organized in form of poster sessions. Optional PhD Forum submissions should be abstracts or full papers and will be published in informal proceedings. Submissions are accepted from March 27 to June 3. The final registration deadline is June 4.